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Applicant(s)/Patent under Reexamination

10/542,388

Examiner

Art Unit

BAKER ET AL.

Seung H. Lee

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Class	Subclass	Date	Examiner
235	439	3/21/2007	SL
235	441	3/21/2007	SL
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH (INCLUDING SEAF	NOTES CH STRA	TEGY)	<u> </u>	
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235/492(see printotus)	3/21	/2007	SL	
PCT cites	3/21	/2007	SL	
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